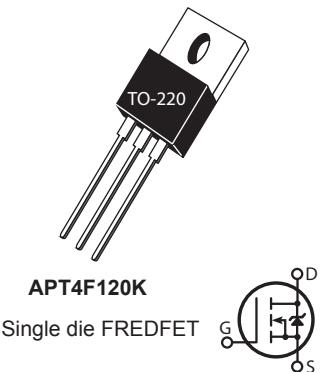


N-Channel FREDFET

Power MOS 8™ is a high speed, high voltage N-channel switch-mode power MOSFET. This 'FREDFET' version has a drain-source (body) diode that has been optimized for high reliability in ZVS phase shifted bridge and other circuits through reduced t_{rr} , soft recovery, and high recovery dv/dt capability. Low gate charge, high gain, and a greatly reduced ratio of C_{rss}/C_{iss} result in excellent noise immunity and low switching loss. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control di/dt during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency.



FEATURES

- Fast switching with low EMI
- Low t_{rr} for high reliability
- Ultra low C_{rss} for improved noise immunity
- Low gate charge
- Avalanche energy rated
- RoHS compliant 

TYPICAL APPLICATIONS

- ZVS phase shifted and other full bridge
- Half bridge
- PFC and other boost converter
- Buck converter
- Single and two switch forward
- Flyback

Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
I_D	Continuous Drain Current @ $T_c = 25^\circ\text{C}$	4	A
	Continuous Drain Current @ $T_c = 100^\circ\text{C}$	3	
I_{DM}	Pulsed Drain Current ^①	15	
V_{GS}	Gate - Source Voltage	±30	V
E_{AS}	Single Pulse Avalanche Energy ^②	310	mJ
I_{AR}	Avalanche Current, Repetitive or Non-Repetitive	2	A

Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Typ	Max	Unit
P_D	Total Power Dissipation @ $T_c = 25^\circ\text{C}$	-	-	225	W
$R_{θJC}$	Junction to Case Thermal Resistance	-	-	.56	°C/W
$R_{θCS}$	Case to Sink Thermal Resistance, Flat, Greased Surface	-	.11	-	
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-55	-	150	°C
T_L	Soldering Temperature for 10 Seconds (1.6mm from case)	-	-	300	
W_T	Package Weight	-	0.07	-	oz
		-	1.22	-	g
Torque	Mounting Torque (TO-220 Package), 4-40 or M3 screw	-	-	10	in-lbf
		-	-	1.1	N·m

Static Characteristics

$T_J = 25^\circ\text{C}$ unless otherwise specified

APT4F120K

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
$V_{BR(DSS)}$	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu\text{A}$	1200			V
$\Delta V_{BR(DSS)}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	Reference to 25°C , $I_D = 250\mu\text{A}$		1.41		$\text{V}/^\circ\text{C}$
$R_{DS(on)}$	Drain-Source On Resistance ^①	$V_{GS} = 10V, I_D = 2\text{A}$		3.42	4.2	Ω
$V_{GS(th)}$	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 0.5\text{mA}$	2.5	4	5	V
$\Delta V_{GS(th)}/\Delta T_J$	Threshold Voltage Temperature Coefficient			-10		$\text{mV}/^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 1200V, T_J = 25^\circ\text{C}$			250	μA
		$V_{GS} = 0V, T_J = 125^\circ\text{C}$			1000	
I_{GSS}	Gate-Source Leakage Current	$V_{GS} = \pm 30V$			± 100	nA

Dynamic Characteristics

$T_J = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
g_{fs}	Forward Transconductance	$V_{DS} = 50V, I_D = 2\text{A}$		4.5		S
C_{iss}	Input Capacitance			1385		
C_{rss}	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{DS} = 25V, f = 1\text{MHz}$		17		pF
C_{oss}	Output Capacitance			100		
$C_{o(cr)}^{④}$	Effective Output Capacitance, Charge Related			40		
$C_{o(er)}^{⑤}$	Effective Output Capacitance, Energy Related	$V_{GS} = 0V, V_{DS} = 0V$ to 800V		20		
Q_g	Total Gate Charge			43		
Q_{gs}	Gate-Source Charge	$V_{GS} = 0$ to 10V, $I_D = 2\text{A}, V_{DS} = 600V$		7		nC
Q_{gd}	Gate-Drain Charge			20		
$t_{d(on)}$	Turn-On Delay Time			7.4		
t_r	Current Rise Time			4.4		ns
$t_{d(off)}$	Turn-Off Delay Time	$V_{DD} = 800V, I_D = 2\text{A}, R_G = 10\Omega$ ^⑥ , $V_{GG} = 15V$		24		
t_f	Current Fall Time			6.9		

Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
I_s	Continuous Source Current (Body Diode)	MOSFET symbol showing the integral reverse p-n junction diode (body diode)			4	A
I_{SM}	Pulsed Source Current (Body Diode) ^①				15	
V_{SD}	Diode Forward Voltage	$I_{SD} = 2A, T_J = 25^\circ\text{C}, V_{GS} = 0V$		0.8	1.3	V
t_{rr}	Reverse Recovery Time	$I_{SD} = 2A$ ^③ , $di_{SD}/dt = 100A/\mu\text{s}$, $V_{DD} = 100V$	$T_J = 25^\circ\text{C}$	170	195	nS
Q_{rr}	Reverse Recovery Charge		$T_J = 125^\circ\text{C}$	330	400	
I_{rm}	Reverse Recovery Current		$T_J = 25^\circ\text{C}$.370		μC
			$T_J = 125^\circ\text{C}$.820		
			$T_J = 25^\circ\text{C}$	4.90		A
			$T_J = 125^\circ\text{C}$	5.40		
dv/dt	Peak Recovery dv/dt	$I_{SD} \leq 2A, di/dt \leq 1000A/\mu\text{s}, V_{DD} = 800V, T_J = 125^\circ\text{C}$			20	V/ns

① Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.

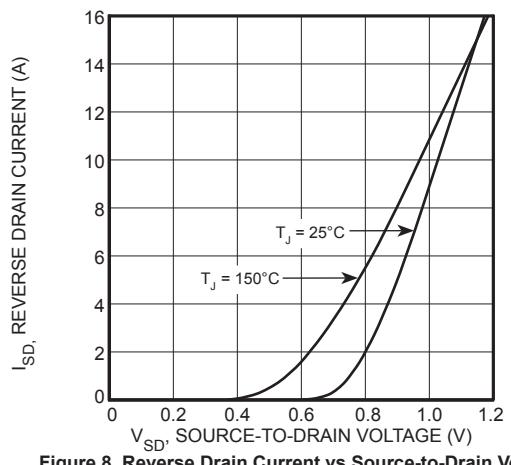
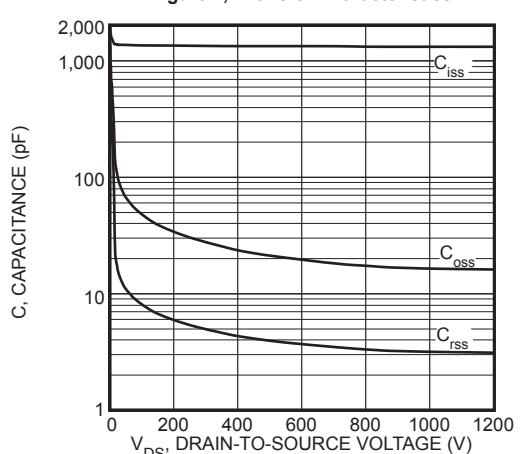
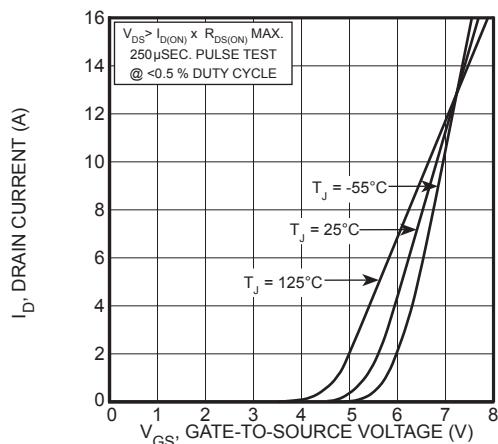
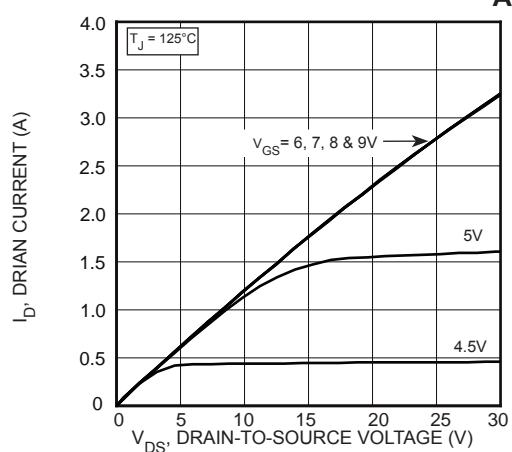
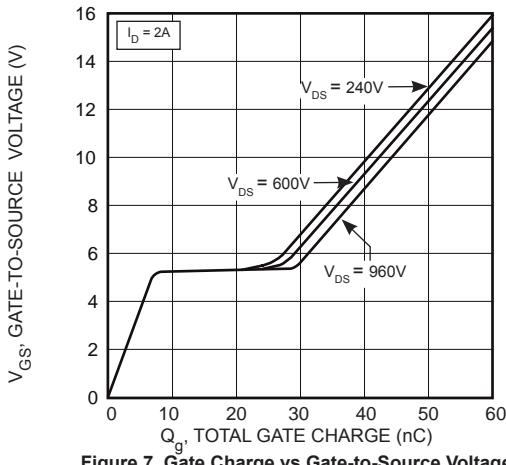
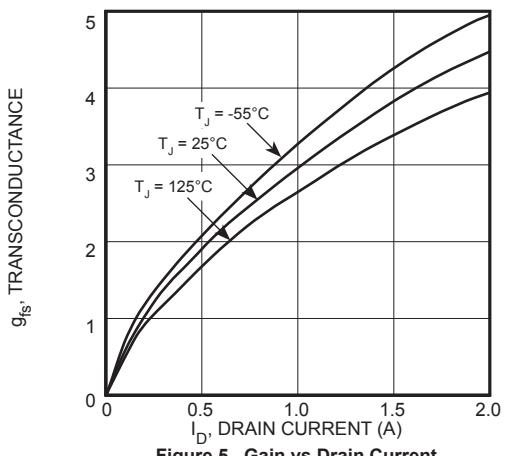
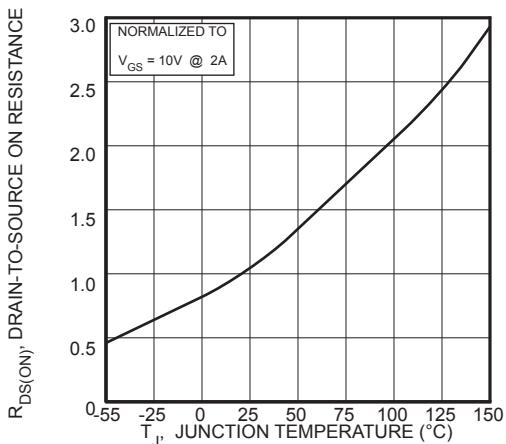
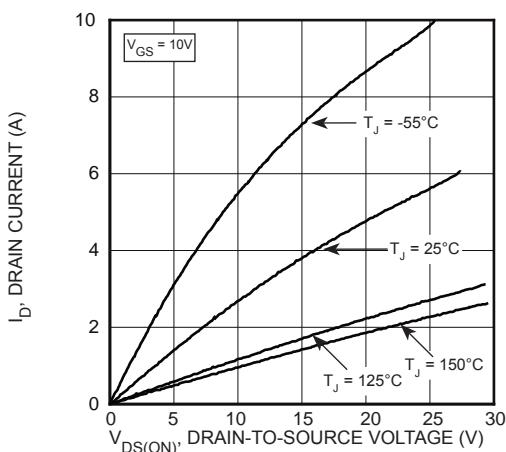
② Starting at $T_J = 25^\circ\text{C}$, $L = 155.0\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 2\text{A}$.

③ Pulse test: Pulse Width < 380μs, duty cycle < 2%.

④ $C_{o(cr)}$ is defined as a fixed capacitance with the same stored charge as C_{oss} with $V_{DS} = 67\%$ of $V_{(BR)DSS}$.

⑤ $C_{o(er)}$ is defined as a fixed capacitance with the same stored energy as C_{oss} with $V_{DS} = 67\%$ of $V_{(BR)DSS}$. To calculate $C_{o(er)}$ for any value of V_{DS} less than $V_{(BR)DSS}$, use this equation: $C_{o(er)} = -8.32E-8/V_{DS}^2 + 3.49E-8/V_{DS} + 1.30E-10$.

⑥ R_G is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)



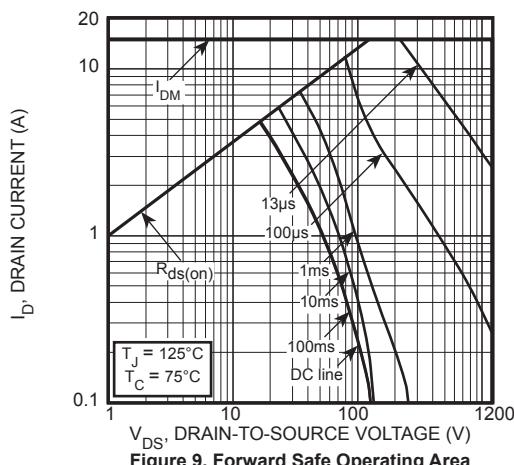


Figure 9, Forward Safe Operating Area

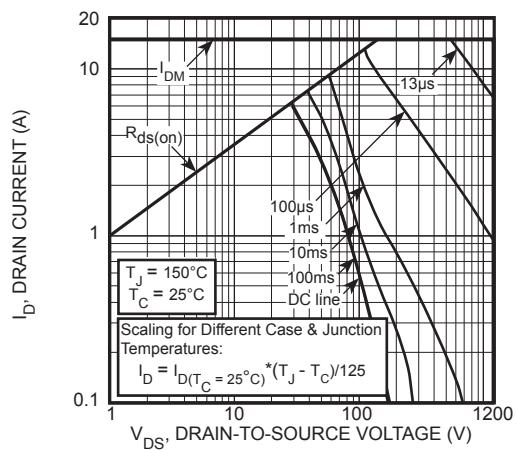


Figure 10, Maximum Forward Safe Operating Area

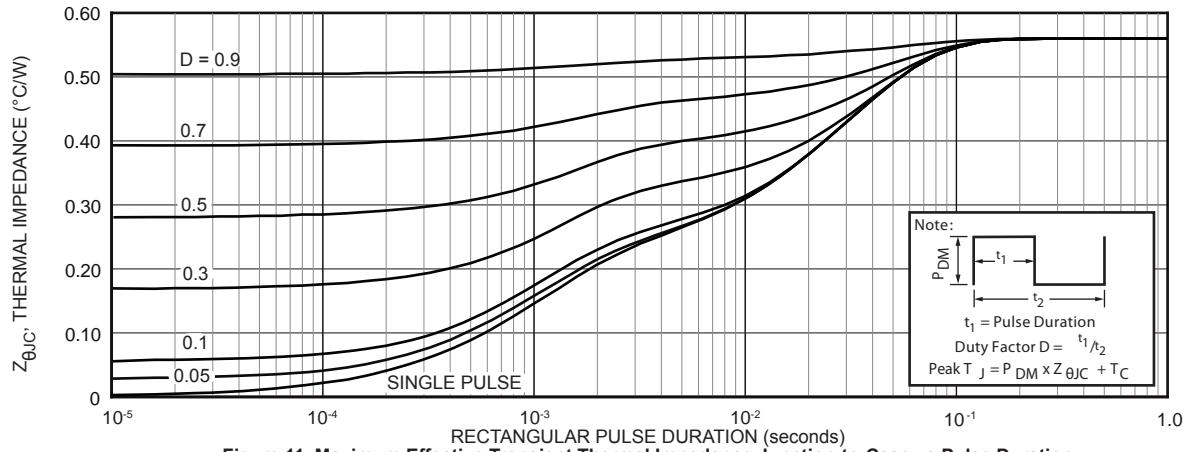
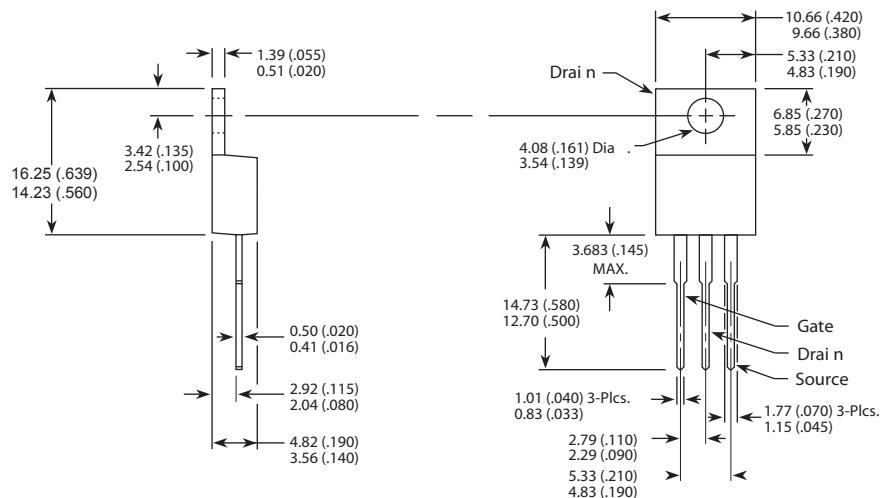


Figure 11. Maximum Effective Transient Thermal Impedance Junction-to-Case vs Pulse Duration

TO-220 (K) Package Outline

e3 100% Sn Plated



Dimensions in Millimeters and (Inches)